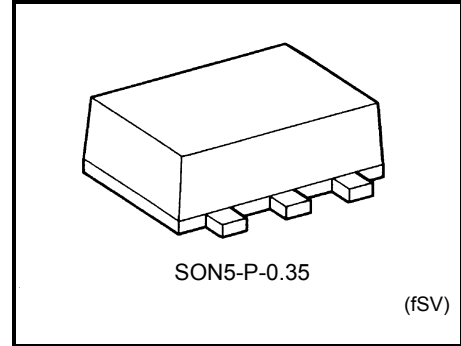


# TC7SH00FS

## 2 Input NAND Gate

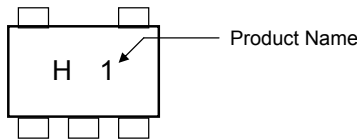
### Features

- High speed:  $t_{pd} = 3.7 \text{ ns}$  (typ.) at  $V_{CC} = 5 \text{ V}$ ,  $15 \text{ pF}$
- Low power dissipation:  $I_{CC} = 2 \mu\text{A}$  (max) at  $T_a = 25^\circ\text{C}$
- High noise immunity:  $V_{NIH} = V_{NIL} = 28\% V_{CC}$  (min)
- Wide operating voltage range:  $V_{CC}$  (opr.) =  $2\sim 5.5 \text{ V}$
- 5.5-V tolerant inputs

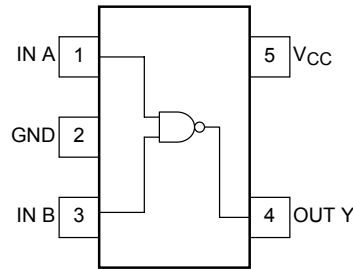


Weight : 0.001 g (Typ.)

### Marking



### Pin Assignment (top view)



### Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

Characteristics	Symbol	Rating	Unit
Supply voltage range	$V_{CC}$	$-0.5\sim 7$	V
DC input voltage	$V_{IN}$	$-0.5\sim 7$	V
DC output voltage	$V_{OUT}$	$-0.5\sim V_{CC} + 0.5$	V
Input diode current	$I_{IK}$	$-20$	mA
Output diode current	$I_{OK}$	$\pm 20$	mA
DC output current	$I_{OUT}$	$\pm 25$	mA
DC $V_{CC}$ /ground current	$I_{CC}$	$\pm 50$	mA
Power dissipation	$P_D$	50	mW
Storage temperature	$T_{stg}$	$-65\sim 150$	$^\circ\text{C}$

**Logic Diagram**



**Truth Table**

A	B	Y
L	L	H
L	H	H
H	L	H
H	H	L

**Recommended Operating Conditions**

Characteristics	Symbol	Rating	Unit
Supply voltage	$V_{CC}$	2~5.5	V
Input voltage	$V_{IN}$	0~5.5	V
Output voltage	$V_{OUT}$	0~ $V_{CC}$	V
Operating temperature	$T_{opr}$	-40~85	°C
Input rise and fall time	dt/dv	0~100 ( $V_{CC} = 3.3 \pm 0.3$ V)	ns/V
		0~20 ( $V_{CC} = 5 \pm 0.5$ V)	

## Electrical Characteristics

### DC Characteristics

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Ta = 25°C			Ta = -40~85°C		Unit	
				Min	Typ.	Max	Min	Max		
High-level input voltage	V <sub>IH</sub>	—	2.0	1.5	—	—	1.5	—	V	
			3.0~5.5	V <sub>CC</sub> × 0.7	—	—	V <sub>CC</sub> × 0.7	—		
Low-level input voltage	V <sub>IL</sub>	—	2.0	—	—	0.5	—	0.5	V	
			3.0~5.5	—	—	V <sub>CC</sub> × 0.3	—	V <sub>CC</sub> × 0.3		
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -50 μA	2.0	1.9	2.0	—	1.9	—	V
				3.0	2.9	3.0	—	2.9	—	
			I <sub>OH</sub> = -4 mA	3.0	2.58	—	—	2.48	—	
				4.5	3.94	—	—	3.80	—	
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub>	I <sub>OL</sub> = 50 μA	2.0	—	0	0.1	—	0.1	V
				3.0	—	0	0.1	—	0.1	
			I <sub>OL</sub> = 4 mA	3.0	—	—	0.36	—	0.44	
				4.5	—	—	0.36	—	0.44	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND	0~5.5	—	—	±0.1	—	±1.0	μA	
Quiescent supply current	I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND	5.5	—	—	2.0	—	20	μA	

**AC Characteristics (Input:  $t_r = t_f = 3 \text{ ns}$ )**

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit	
		V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Typ.	Max	Min	Max		
Propagation delay time	t <sub>pLH</sub>	—	3.3 ± 0.3	15	—	5.5	7.9	1.0	9.5	ns
				50	—	8.0	11.4	1.0	13.0	
	t <sub>pHL</sub>		5.0 ± 0.5	15	—	3.7	5.5	1.0	6.5	
				50	—	5.2	7.5	1.0	8.5	
Input capacitance	C <sub>IN</sub>	—		—	4	10	—	10	pF	
Power dissipation capacitance	C <sub>PD</sub>	(Note)		—	14	—	—	—	pF	

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

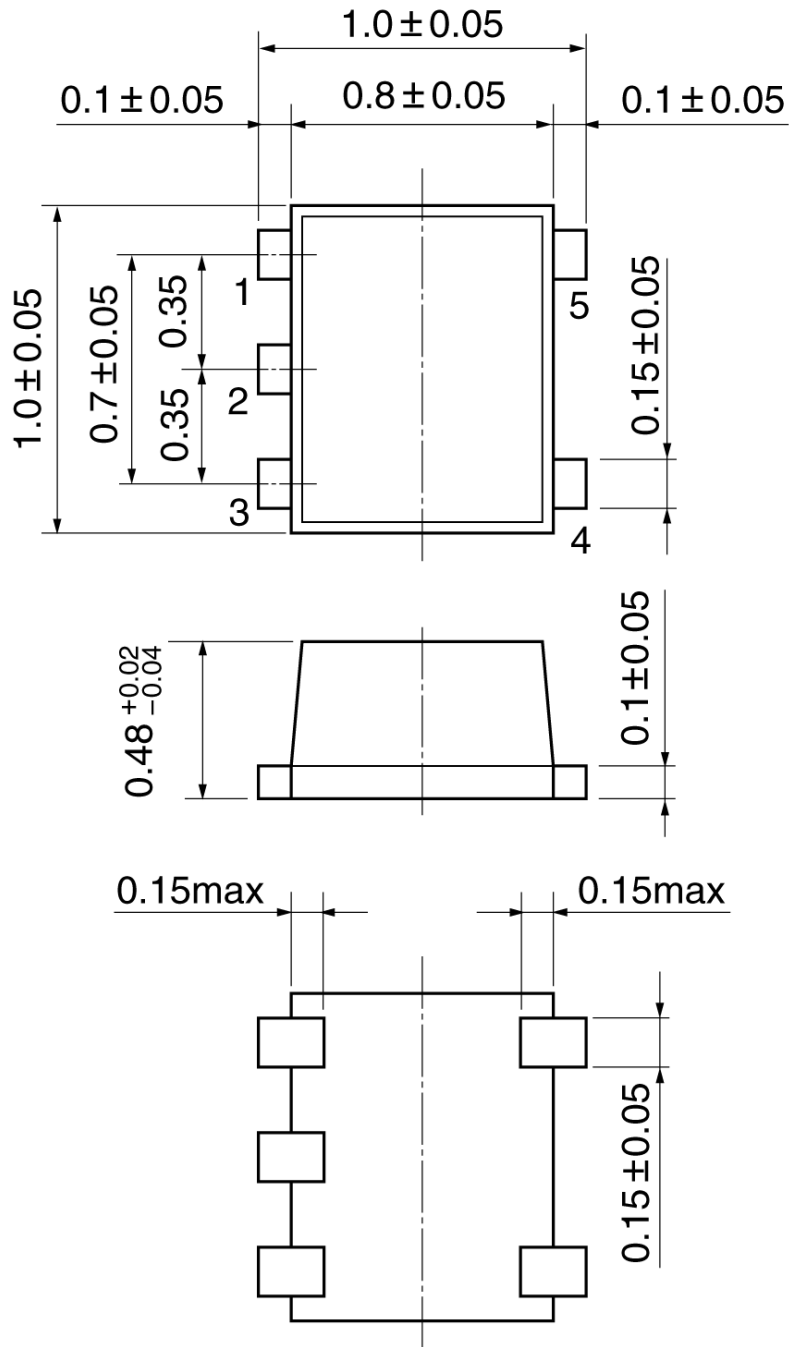
Average operating current can be obtained by the equation:

$$I_{CC} (\text{opr.}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

## Package Dimensions

SON5-P-0.35

Unit:mm



Weight: 0.001 g (typ.)

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